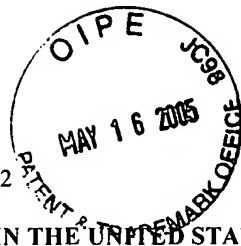


Docket No.: 060188-0652



DAE / JFW

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of : Customer Number: 20277
Masafumi KUBOTA, et al. : Confirmation Number: 9822
Application No.: 10/662,288 : Group Art Unit: 2818
Filed: September 16, 2003 : Examiner: Dang, Phuc T.
For: METHOD FOR FABRICATING SEMICONDUCTOR DEVICE

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Mail Stop 313(c)
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

In accordance with the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, the attention of the Patent and Trademark Office is hereby directed to the reference listed on the attached form PTO-1449. It is respectfully requested that the reference be expressly considered during the prosecution of this application, and that the reference be made of record therein and appear among the "References Cited" on any patent to issue therefrom.

In response to the Information Disclosure Statements filed on April 29, 2005 and March 14, 2005, a English translation of the foreign office action, is submitted herewith for the Examiner's information. The following references JP 2002-057301, JP 2001-168325 (submitted on March 14, 2005) and JP 2002-164514 (submitted April 29, 2005) are cited in the Japanese Notice of Reasons of Rejection

Please charge any shortage in fees due in connection with the filing of this paper, including extension of time fees, to Deposit Account 500417 and please credit any excess fees to such deposit account.

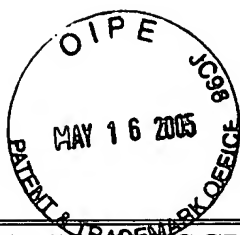
Respectfully submitted,

McDERMOTT WILL & EMERY LLP

[Signature]
Michael E. Fogarty
Registration No. 36,139

Please recognize our Customer No. 20277 as our
correspondence address.

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Date: May 16, 2005



SHEET 1 OF 1

INFORMATION DISCLOSURE CITATION IN AN APPLICATION (PTO-1449)				ATTY. DOCKET NO. 060188-0652		SERIAL NO. 10/662,288	
				APPLICANT Masafumi KUBOTA, et al.			
				FILING DATE September 16, 2003		GROUP 2818	
U.S. PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Code ₂ (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear		
		US					
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FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + -Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes No	
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
EXAMINER'S INITIALS	CITE NO.	Include name of the author (in CAPITAL LETTERS), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.					
		NOTICE OF REASONS OF REJECTION (OFFICE ACTION) Mailing Date: April 19, 2005 Patent Application Number: 2002-319909 Drafted Date: April 12, 2005 Examiner: Eiichi TANAKA Agent: Hiroshi MAEDA (and 7 other persons) pp. 1-3 (English Translation)					
EXAMINER				DATE CONSIDERED			

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

1 Applicant's unique citation designation number (optional). 2 Applicant is to place a check mark here if English language Translation is attached.